



International Electronics Manufacturing Initiative

*iNEMI Meetings
OFC/NFOEC 2006
Conference
March 6, 2006
Anaheim Marriott*

10:00 – 10:15 am

Introductions and iNEMI Overview:
David Godlewki, iNEMI

iNEMI Fiber Connector End-Face Inspection Project

Project Chair: Tatiana Berdinskikh, Celestica

Project Co-chair: Heather Tkalec, Alcatel, Canada

10:15 – 11:00 am

Development of Cleanliness Specifications for
Single-Mode Connectors with 2.5 and 1.25 mm
Ferrules:

Tatiana Berdinskikh, Celestica International Inc.,
Sun-Yuan Huang, Intel Corp., Douglas H. Wilson,
PVI Systems Inc.

11:00 - 11:15 am

Insertion Loss/Return Loss Testing Process for
Multimode Connectors:

David W.Fisher, Tyco Electronics

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| 11:15 – 11:45 am | Correlation of Contamination-to-Loss on Multimode Connector Endfaces:
Steve Lytle, Westover Scientific |
| 11:45 am – 12.15 pm | Proposed cleanliness specification of STUB endface:
Yutaka Sadohara, Sumitomo Electric |
| 12.15 pm – 1:00 pm | Break |
| 1:00 – 1:30 pm | Investigation of the ESD effects on mated fiber optic connectors:
Tatiana Berdinskikh, and Jeno Chen, Celestica International Inc.
John M Culbert, and Robert Mays, Megladon Manufacturing Group |

1:30 – 2:00 pm

Publications of IPC-8497-1, *Cleaning Methods and Contamination Assessment for Optical Assembly*, and future research strategy:

Tatiana Berdinskikh, Celestica International Inc.

iNEMI Optoelectronic TIG — Potential Projects

Champion: Tatiana Berdinskikh, Celestica International Inc.

2:00 – 4:00 pm

Review the iNEMI Optoelectronics Technology Roadmap: David Godlewski, Inemi

Discuss industry needs and potential new projects to address those needs: open discussion — all